

Application/Contro	ol No. Applicant(s) Reexaminati	/Patent under ion
10/705,890	OESCH, YV	/ES
Examiner	Art Unit	
Duc M. Nguyen	2685	

SEARCHED				
Class	Subclass	Date	Examiner	
455	41.1 41.2 41.3			
	42->45			
	567			
	572			
	575.6			
	90.1->			
	->90.3			
	59 106			
	347->349			
379	428.02			
	433.1			
	433.11			
	441 443			
	447	2/15/2006	DN	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
EAST	2/15/2006	DN
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